

JPW

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c))			Docket No. P 6079.12009	
In Re Application Of: Ram Voorakaranam et al.				
Serial No. 10/692,586	Filing Date Oct. 23, 2003	Examiner		Group Art Unit 2858
Title: METHOD FOR USING AN ALTERATE PERFORMANCE TEST TO REDUCE TEST TIME AND IMPROVE MANUFACTURING YIELD				
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37 CFR 1.97(b)				
1. <input checked="" type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.				
37 CFR 1.97(c)				
2. <input type="checkbox"/> The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:				
<input type="checkbox"/> the statement specified in 37 CFR 1.97(e);				
OR				
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TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT

(Under 37 CFR 1.97(b) or 1.97(d))

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Group Art Unit

2858

**METHOD FOR USING AN ALTERATE PERFORMANCE TEST TO REDUCE TEST TIME AND
IMPROVE MANUFACTURING YIELD****Payment of Fee**

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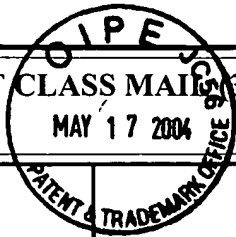
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Docket No.

P 6079.12009

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Invention: **METHOD FOR USING AN ALTERNATE PERFORMANCE TEST TO REDUCE TEST TIME AND IMPROVE MANUFACTURING YIELD**

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INFORMATION DISCLOSURE CITATION

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Oct. 23, 2003

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	US2002/0133772 A1	9/19/02	Voorakaranam et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Chatterjee et al., Ardext FASTest: A New Approach For Rapid Testing of Analog ICs, http://www.ardext.com/documents/ardext_fast_technology.htm
		Ram Voorakaranam, et al., "A Signature Test Framework for Rapid Production Testing in RF Circuits," Design, Automation and Test in Europe, 2002, 6 pages

EXAMINER

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) P 6079.12009	Application Number 10/692,586
		Applicant(s) Ram Voorakaranam et al.	
		Filing Date October 23, 2003	Group Art Unit

*EXAMINER INITIAL	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>
	Ram Voorakaranam, et al., "Test Generation for Accurate Prediction of analog Specifications," Proceedings, VLSI Test Symposium, 2000, pps. 137-142
	Pramodchandran N. Variyam, et al., "Specification-Driven Test Design for Analog Circuits," IEEE Transactions on Computer-Aided Design of Integrated Circuits," Vol. 19, No. 10, pps. 1189-1201
	Mark Burn and G.W. Roberts, "Data Analysis," An Introduction to Mixed-Signal IC Test and Measurement, Oxford University Press, 2001, pps. 597-639
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